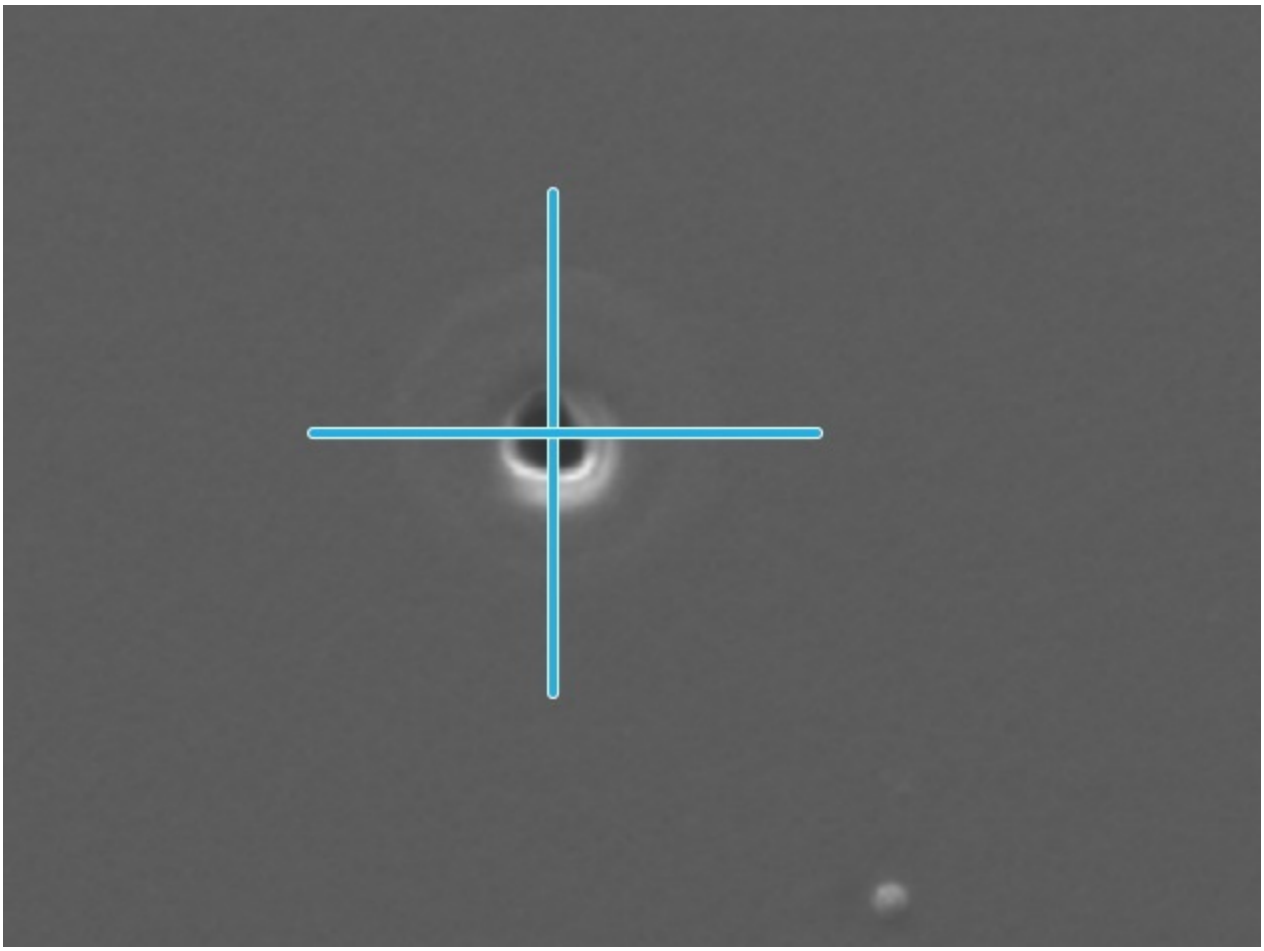
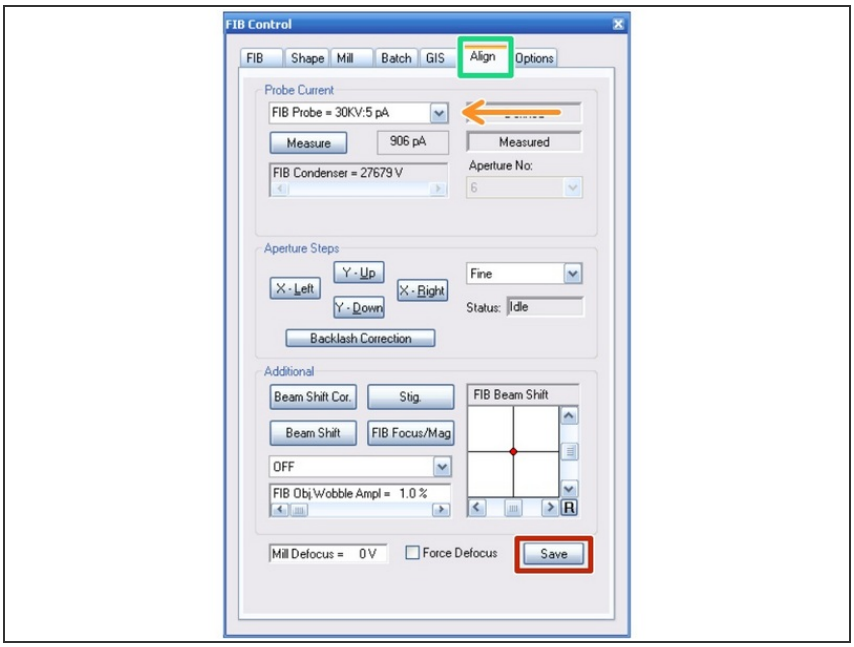
Setting FIB Probe alignments

Short manual explaining the steps to correct focus, astigmatism and beam shift of the FIB probe currents

Written By: José Maria Mateos Melero

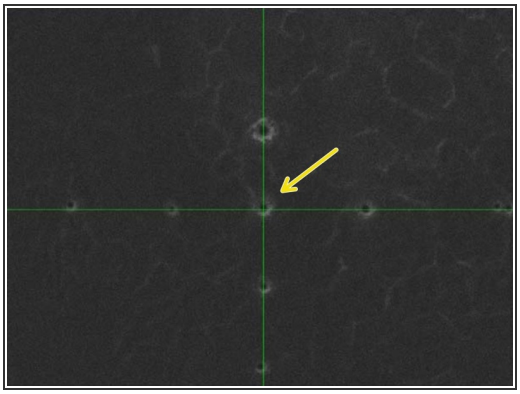


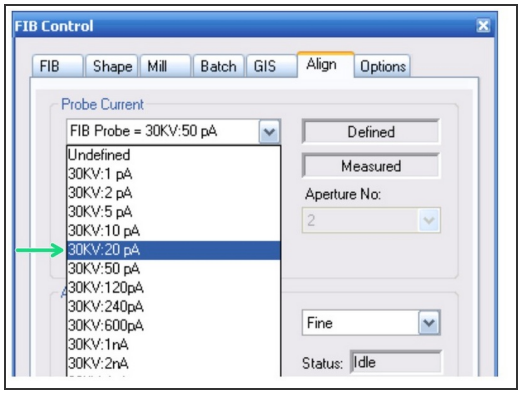
Step 1 — Prerequisities and Apertures alignment

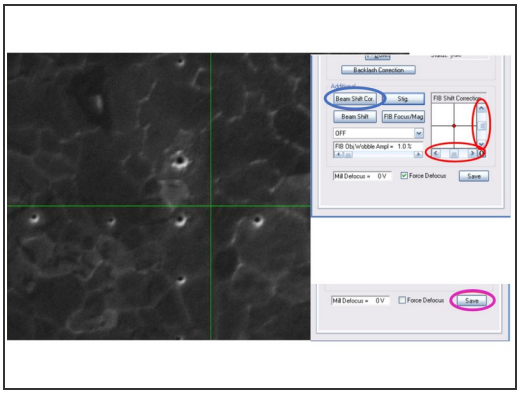


- 1. SEM and FIB are switched on. 2. Bring sample to coincident point. 3. Center on a border of the grid. 4. FIB apertures have been initialized.
- In the FIB Control Menu. Select **Align** tab.
- Select the 30kV/50pA probe current (reference probe current)
- Focus the specimen surface: Use **Focus** and **Stigmation**. Click on Save.
- Change the probe current and repeat these steps for each current.

Step 2 — Adjusting beam shift correction







- The beam shift correction is used to correct the different beam positions of the different probe current settings.
- The 30kV:50pA probe current is the reference current where no correction is applied.
- Select the crosshairs and bring a recognizable feature to the center.
- In the FIB Control/Align tab, select the next smaller probe current from the drop-down menu.
- If the feature is shifted to another position: Move the feature to the original position by using the beamshift correction. Click on **Beam Shift Cor.**
- Move the crosshairs with the sliders.
- Click on **Save** to save the adjustments. Repeat these steps for all smaller probe current.
- Now before adjusting the higher probes switch back to the 30kV/50pA and if necessary center the feature by moving the stage before changing to the following higher currents and proceed as above for the rest of probe currents.